## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of: Walter SCHWARZENBACH et al.

Confirmation No.

Application No.:

Group Art Unit:

Filing Date:

Sir:

Examiner:

For: METHOD OF MAKING CAVITIES IN A

SEMICONDUCTOR WAFER

Atty. Docket No.: 4717-9200

## **INFORMATION DISCLOSURE STATEMENT**

Commissioner for Patents P.O. Box 1450 Alexandria, Virginia 22313-1450

Pursuant to applicants' duty of disclosure under 37 C.F.R. 1.56, enclosed are copies of nine (9) references for the Examiner's review and consideration. These references are listed on the enclosed Form PTO-1449.

These references were cited in the European Search Report a copy of which is enclosed. It is respectfully requested that these references be made of record in this application by the Examiner's completion and return of the PTO Form 1449.

No fee or certification is believed to be due for this submission since the references are being submitted concurrent with the filing of this application. Should any fees be required, however, please charge such fees to **Winston & Strawn** Deposit Account No. 50-1814.

Date:

Respectfully submitted,

Allan A. Fanucci

(Reg. No. 30,256)

WINSTON & STRAWN LLP CUSTOMER NO. 28765

(212) 294-3311

Enclosures

NY:828763.1

LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary)							ATTY. DOCKET NO.:			APPLICATION NO.:		
							4717-9200					
							APPLICANT:					
							Walter SCHWARZENBACH et al.					
							FILING DATE:		GROUP:			
				U.S.	PATE	NT DOCU	MENTS					
*EXAMINER INITIAL		DOCUMENT NUMBER	DOCUMENT NUMBER DATE				NAME	CLASS	SUBCLASS		DATE IF PRIATE	
	AA	4,956,314	9/	1990	Tam et al.			437	241			
	AB	5,576,250	11/	1996	Diem et al.			437	228			
	AC	5,780,885	7/	1998	Diem et al.			257	254			
	AD	5,976,945	11/	/1999	Chi et al.			438	386			
	AE	6,171,923 B1	1/2001		Chi et al.			438	386			
	AF	6,335,292 B1	1/2002		Li et al.			438	714			
				FORE	EIGN PA	ATENT DOC	UMENTS					
		DOCUMENT NUMBER	12/2000 Fi			COUNTRY		SUBCLASS	TRANSLATION			
	-	2.700.065							YES	NO		
	AG	2 700 065 (with English Abstr			France				X			
	АН	2 795 554 (with English Abstr			France				x			
	AI	JP 06132262 (with English Abstr			Japan				х			
	AJ											
	AK											
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)												
	AL											
	AM											
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EXAMINER						DATE	DATE CONSIDERED					
*EXAM	IINER:	Initial if reference considered in conformance and no	ed, wh	nether or	not cita nclude	tion is in co	nformance with MPEP 609; D	raw line the	nrough citat	ion if r	not	
in conformance and not considered. Include copy of this form with next communication to applicant.												